

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTORNEY DOCKET NO.
1391.1056APPLICATION NO. 10/786,083
~~Unassigned~~

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

FIRST NAMED INVENTOR
Ching Y. Suen et al.FILING DATE
February 26, 2004GROUP ART UNIT 2624
~~Unassigned~~

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES NO
/GD/	AG	5-12491	01/22/93	Japan			X
	AH						
	AI						
	AJ						

OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

/GD/	AK	Simon X. LIAO et al., "On Image Analysis by Moments," IEEE Trans. on PAMI, Vol. 18, No. 3, March 1996, pp. 254-266 (March 1996).
/GD/	AL	S. SATOH et al., "Evaluation of Two Neocognitron-type Models for Recognition of Rotated Patterns," ICONIP 2000, WBP-04 (2000), pp.295-299.
/GD/	AM	Q. XIE et al., "A Construction of Pattern Recognition System Invariant to Translation, Scale-Change and Rotation Transformation of Patterns," Vol. 27, No. 10, pp. 1167-1174 (1991).
/GD/	AN	H. Hase et al., "Alignment of Free Layout Color Texts for Character Recognition," Proceeding of the Sixth International Conference on Document Analysis and Recognition, September 10-13, 2001, pp. 932-936 (Sept. 2001).
/GD/	AO	Hiroshi MURASE et al., "Three-dimensional object recognition using two-dimensional collation - parametric Eigen space techniques, IECE Trans. vol. J77-D-II, no. 11, Nov. 1994, pp.2179-2187 (Nov. 1994).

EXAMINER /Gregory Desire/	DATE CONSIDERED 05/14/2007
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	